

# Search Notes



Application/Control No.

10/820,359

Examiner

Mark T. Le

Applicant(s)/Patent under Reexamination

CHANG, EDDIE

Art Unit

3617

## SEARCHED

Class	Subclass	Date	Examiner
191	12.2A	7/6/05	
	12.4		
381	74		
	77		
379	438		
455	350		
	351		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
searched EAST	7/7/05	